

# Resource Summary Report

Generated by RRID on Aug 5, 2026

## JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)

RRID:SCR\_020196

Type: Tool

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### Proper Citation

JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)  
(RRID:SCR\_020196)

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### Resource Information

**URL:** <https://www.jeolusa.com/PRODUCTS/Scanning-Electron-Microscopes-SEM/Soft-X-ray-Emission-Spectrometer>

**Proper Citation:** JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM) (RRID:SCR\_020196)

**Description:** Scanning electron microscope that provides excellent light element detection and superb sensitivity that is best for chemical shift analysis of light elements

**Resource Type:** instrument resource

**Keywords:** Jeol, JEOL, Scanning Electron Microscope, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM)

**Resource ID:** SCR\_020196

**Alternate IDs:** Model\_Number\_Soft X-Ray Emission Spectrometer

**Record Creation Time:** 20220129T080349+0000

**Record Last Update:** 20260801T190641+0000

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### Ratings and Alerts

No rating or validation information has been found for JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM).

No alerts have been found for JEOL: Soft X-Ray Emission Spectrometer Scanning Electron Microscope (SEM).

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.